

AMENDMENTS TO THE CLAIMS

Please amend the claims as follows:

1. (Previously Presented) A method of testing a power supply in an information handling system (IHS), the method comprising:
 - activating a diagnostic test circuit in the power supply for a first time period; and
 - supplying power, by the power supply, to a test load resistor in the power supply for a second time period within the first time period, the second time period being controlled by the diagnostic test circuit; and
 - monitoring a power good signal from a housekeeping controller which monitors voltages within the power supply.
2. (Original) The method of claim 1 wherein the second time period is sufficiently short to prevent overheating of the test load resistor.
3. (Original) The method of claim 1 including inactivating the diagnostic test circuit after the first time period has expired.
4. (Original) The method of claim 1 including delaying the supplying of power to the test load resistor for the duration of a cool down time delay period to allow the test load resistor to cool.
5. (Cancelled).
6. (Currently Amended) The method of claim-5_1 including testing to determine if the power good signal indicates power good.

7. (Original) The method of claim 6 including activating a first indicator if the power good signal indicates power good, thus indicating a properly functioning power supply.
8. (Original) The method of claim 6 including testing to determine if the power supply is connected to a system board of the IHS if the power good signal does not indicate power good.
9. (Original) The method of claim 8 including activating a second indicator if the power supply is not connected to the system board of the IHS and the power good signal does not indicate power good, thus indicating an improperly functioning power supply.
10. (Original) The method of claim 9 including activating a third indicator if the power supply is connected to the system board of the IHS and the power good signal does not indicate power good, thus indicating that the results of diagnostic testing are undetermined.
11. (Original) The method of claim 7 including inactivating the first indicator when the first time period has expired.
12. (Original) The method of claim 9 including inactivating the second indicator when the first time period has expired.
13. (Original) The method of claim 10 including inactivating the third indicator when the first time period has expired.

14. (Original) The method of claim 1 wherein the test is initiated by a customer in response to an instruction received from a call center from which service is requested.
15. (Currently Amended) An information handling system (IHS) comprising:
 - a system board including a processor; and
 - a power supply for supplying power to the system board, the power supply including:
 - a diagnostic test actuation mechanism;
 - a diagnostic test circuit which in response to actuation of the test actuation mechanism is activated for a first time period; and
 - a test load resistor to which power is supplied by the power supply for a second time period within the first time period, the second time period being controlled by the diagnostic test circuit, wherein the power supply includes a housekeeping controller for monitoring voltages within the power supply to provide a power good signal.
16. (Original) The IHS of claim 15 wherein the second time period is sufficiently short to prevent overheating of the test load resistor.
17. (Original) The IHS of claim 15 wherein the diagnostic test circuit is inactivated after the first time period has expired.
18. (Original) The IHS of claim 15 wherein the supplying of power to the test load resistor is delayed for the duration of a cool down time delay period to allow the test load resistor to cool.
19. (Cancelled).

20. (Currently Amended) The IHS of claim 19 15 wherein the power supply includes a first indicator which is activated if the power good signal indicates power good, thus indicating a properly functioning power supply.
21. (Original) The IHS of claim 20 wherein the power supply includes a second indicator which is activated if the power supply is not connected to the system board of the IHS and the power good signal does not indicate power good, thus indicating an improperly functioning power supply.
22. (Original) The IHS of claim 20 wherein the power supply includes a third indicator which is activated if the power supply is connected to the system board of the IHS and the power good signal does not indicate power good, thus indicating undetermined results.
23. (Original) The IHS of claim 15 wherein the diagnostic test actuation mechanism is a switch which can be activated by a user.
24. (Original) The IHS of claim 15 wherein the diagnostic test actuation mechanism is an AC power detector.
25. (Currently Amended) An information handling system (IHS) comprising:
 - a chassis;
 - a microprocessor mounted on a system board in the chassis;
 - a storage coupled to the microprocessor; and
 - a power supply for supplying power to the system board, the power supply including:
 - a diagnostic test actuation mechanism;

a diagnostic test circuit which in response to actuation of the test actuation mechanism is activated for a first time period; and
a test load resistor to which power is supplied by the power supply for a second time period within the first time period, the second time period being controlled by the diagnostic test circuit, wherein the power supply includes a housekeeping controller for monitoring voltages within the power supply to provide a power good signal.

26. (Previously Presented) The IHS of claim 25 wherein the second time period is sufficiently short to prevent overheating of the test load resistor.
27. (Previously Presented) The IHS of claim 25 wherein the diagnostic test circuit is inactivated after the first time period has expired.
28. (Previously Presented) The IHS of claim 25 wherein the supplying of power to the test load resistor is delayed for the duration of a cool down time delay period to allow the test load resistor to cool.